

Search Notes

Application/Control No.

10/626,693

Examiner

Madeleine AV Nguyen

Applicant(s)/Patent under
Reexamination

MEYER, JOHN F.

Art Unit

2625

SEARCHED

Class	Subclass	Date	Examiner
update		10/3/2007	AV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East	10/3/2007	AV